

select(1)

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NAME

select – general selection program

SYNOPSIS

select

DESCRIPTION

select probes the classification file using slct. By default, the classification file is assumed to be \$MYSIFDEC/CLASSF.DB, but the slct program allows the user to give a full path name for the classification file, thereby allowing both the filename and the directory to be changed.

ENVIRONMENT

SIFDECODE

Parent directory for SIFDecode.

MASTSIF

A pointer to the directory containing the CUTEst/SIFDecode problems collection.

AUTHORS

I. Bongartz, A.R. Conn, N.I.M. Gould, D. Orban and Ph.L. Toint

SEE ALSO

CUTEst: a Constrained and Unconstrained Testing Environment with safe threads,
N.I.M. Gould, D. Orban and Ph.L. Toint,
Technical Report, Rutherford Appleton Laboratory, 2013.

CUTer (and SifDec): A Constrained and Unconstrained Testing Environment, revisited,
N.I.M. Gould, D. Orban and Ph.L. Toint,
ACM TOMS, **29**:4, pp.373-394, 2003.

CUTE: Constrained and Unconstrained Testing Environment,
I. Bongartz, A.R. Conn, N.I.M. Gould and Ph.L. Toint,
ACM TOMS, **21**:1, pp.123-160, 1995.

classall(1), classify(1).

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